

WEST Search History

DATE: Wednesday, September 21, 2005

<u>Hide?</u>	<u>Set Name</u>	<u>Query</u>	<u>Hit Count</u>
<i>DB=PGPB; PLUR=YES; OP=ADJ</i>			
<input type="checkbox"/>	L6	717/168.ccls.	268
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>			
<input type="checkbox"/>	L5	l2 and (depend\$6 same (updat\$5 or upgrad\$5))	38
<input type="checkbox"/>	L4	l2 and L3	22
<input type="checkbox"/>	L3	717/168-178.ccls.	2081
<input type="checkbox"/>	L2	(install\$6 with (service pack))	125
<i>DB=USPT; PLUR=YES; OP=ADJ</i>			
<input type="checkbox"/>	L1	(install\$6 with (service pack))	31

END OF SEARCH HISTORY


[Subscribe \(Full Service\)](#) [Register \(Limited Service, Free\)](#) [Login](#)
Search: The ACM Digital Library The Guide


THE ACM DIGITAL LIBRARY
[Feedback](#) [Report a problem](#) [Satisfaction survey](#)
Terms used [install service pack](#)

Found 1 of 161,645

Sort results by

[Save results to a Binder](#)
[Try an Advanced Search](#)

Display results

[Search Tips](#)
[Try this search in The ACM Guide](#)
[Open results in a new window](#)

Results 1 - 1 of 1

Relevance scale

1 [Proceedings of the 2004 conference on Designing interactive systems: processes, practices, methods, and techniques](#)



David Benyon, Paul Moody, Daniel Gruen, Irene McAra-McWilliam
August 2004 proceeding, ACM Press

Additional Information: [full citation](#), [abstract](#)

Welcome to DIS2004, the ACM conference on Designing Interactive Systems. We have a fantastic program of papers, posters, panels, lab tours, exhibits and design competition packed into three days. A veritable feast of the best examples of interactive systems design with some challenging and provocative views on the processes and theories of the design of interactive media. One of the key locations in the development of interactive media is the Massachusetts Institute of Technology, MIT and we are ...

Results 1 - 1 of 1

The ACM Portal is published by the Association for Computing Machinery. Copyright © 2005 ACM, Inc.

[Terms of Usage](#) [Privacy Policy](#) [Code of Ethics](#) [Contact Us](#)

 Useful downloads: [Adobe Acrobat](#) [QuickTime](#) [Windows Media Player](#) [Real Player](#)

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

SEARCH RESULTS**BROWSE****SEARCH****IEEE Xplore GUIDE**

Results for "((install<in>ab) <and> (service pack<in>ab))"

 e-mailYour search matched **0** documents.A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance in Descending** order.[» Search Options](#)[View Session History](#)[Modify Search](#)[New Search](#) [»](#) Check to search only within this results setDisplay Format: Citation Citation & Abstract[» Key](#)

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

No results were found.

Please edit your search criteria and try again. Refer to the Help pages if you need assistance.

[Help](#) [Contact Us](#) [Privacy & ...](#)

© Copyright 2005 IEEE ...

Indexed by

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

SEARCH RESULTS[BROWSE](#)[SEARCH](#)[IEEE Xplore GUIDE](#)

Results for "((install<in>metadata) <and> (service pack<in>metadata))"

 e-mail

Your search matched 0 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by **Relevance in Descending** order.[» Search Options](#)[View Session History](#)[Modify Search](#)[New Search](#) [»](#) Check to search only within this results setDisplay Format: Citation Citation & Abstract[» Key](#)

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

No results were found.

Please edit your search criteria and try again. Refer to the Help pages if you need assistance.

Indexed by
[Help](#) [Contact Us](#) [Privacy & ...](#)

© Copyright 2005 IEEE ...